

An X-ray fluorescence spectrometer using CMOS-sensors

Dennis Doering, Michael Deveaux

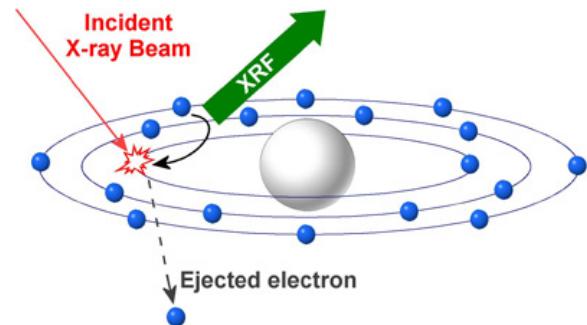
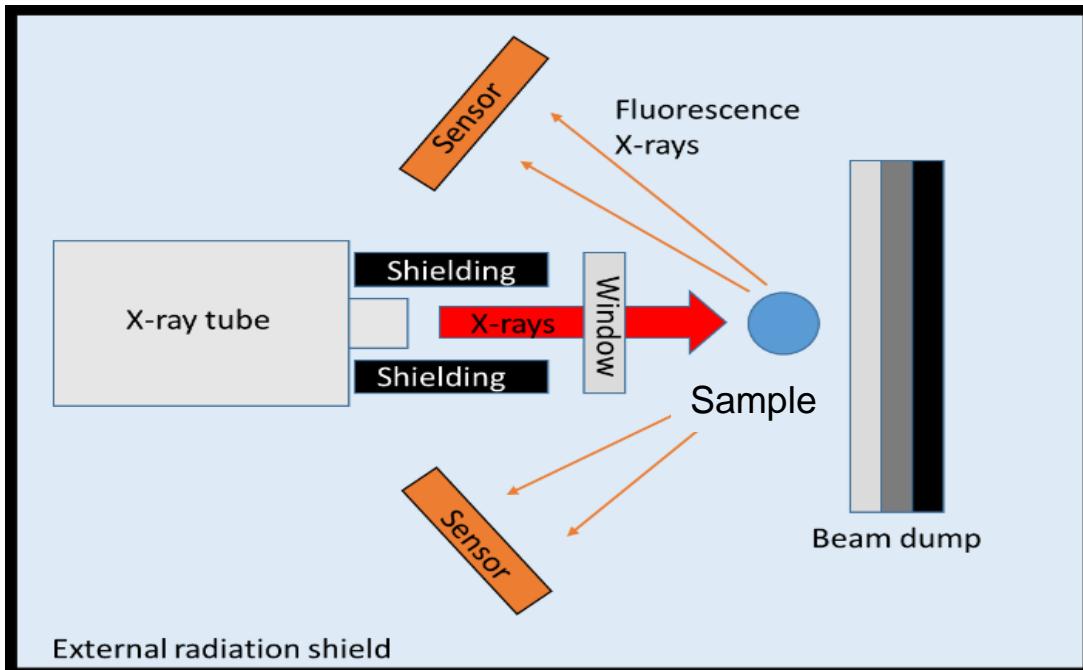
Institut für Kernphysik Frankfurt
for the CBM-MVD-collaboration

Sensor development: IPHC Strasbourg

- 1) Real-time water analysis using XRF**
- 2) CMOS-Sensors**
- 3) Reconstruction of the energy information**
- 4) Improving the quantum efficiency**

Application: X-ray spectrometer

Monitoring water quality and trigger on traces of pollution



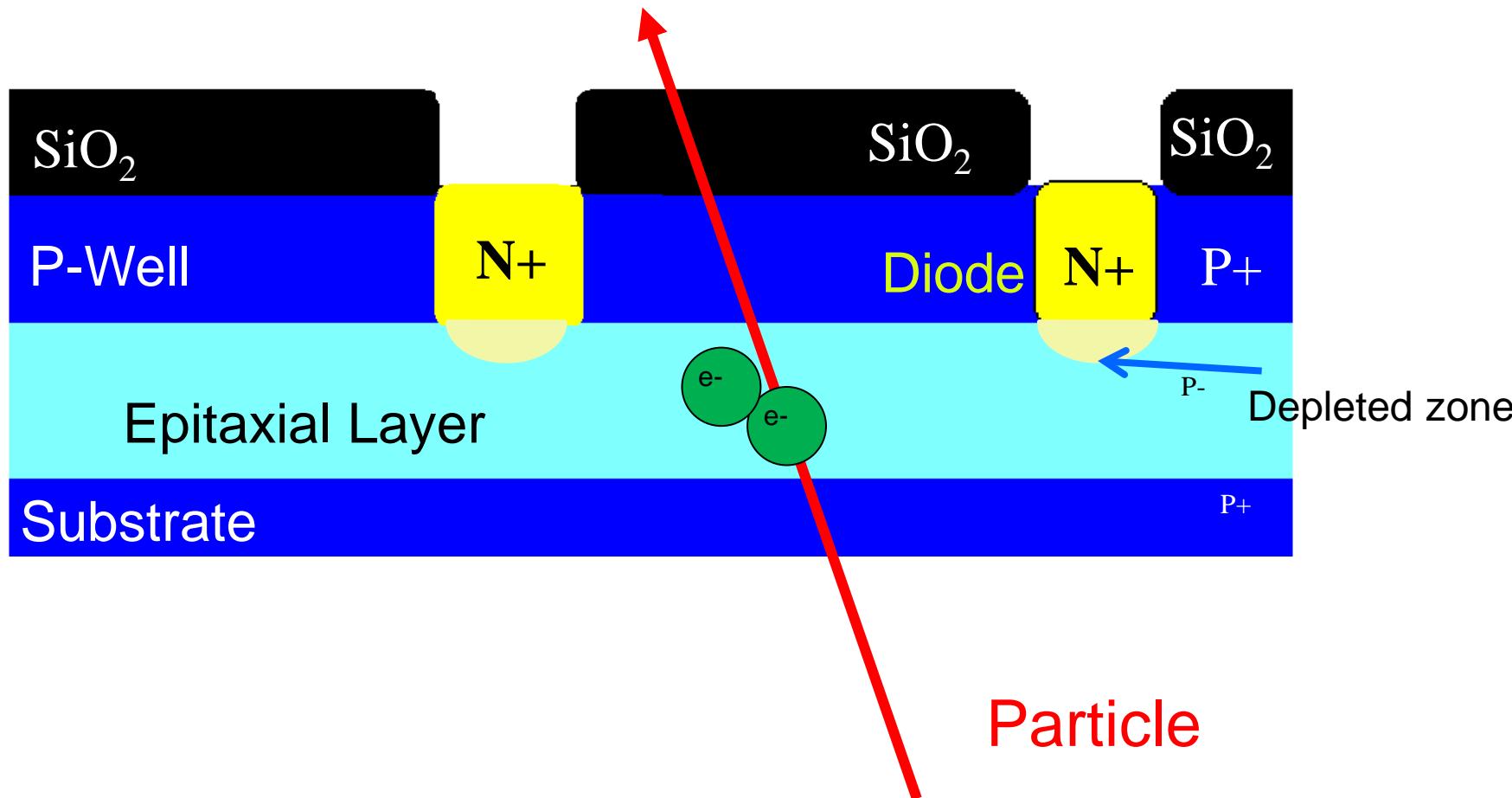
Identifying elements via their characteristic X-ray-fluorescence lines (XRF)

Required sensor features:

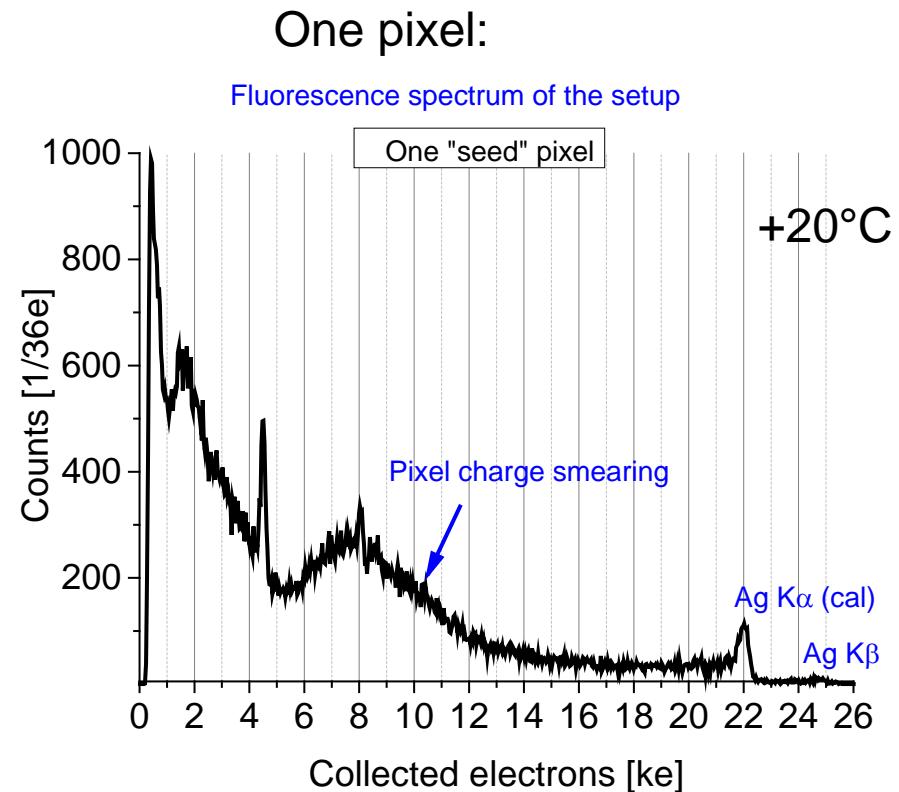
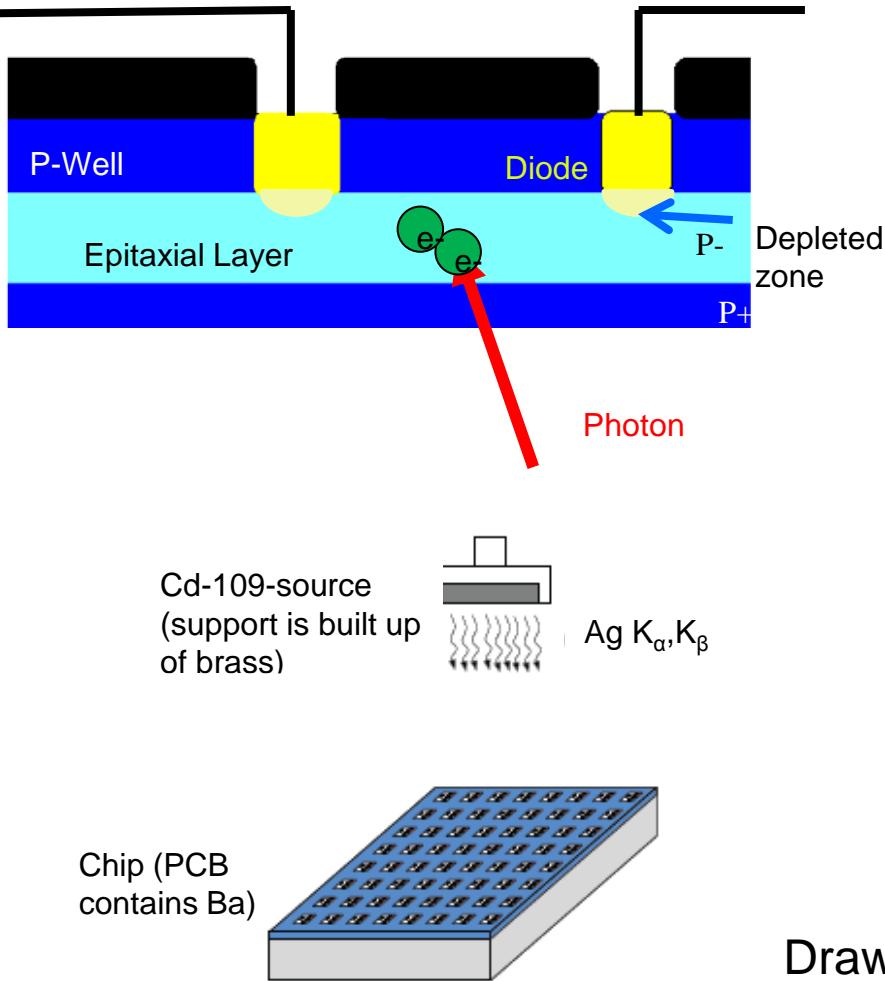
- Good energy resolution
- High-rate capability
- Low noise
- Low production costs

⇒ Adapted CMOS-sensors

Operation principle of CMOS-sensors

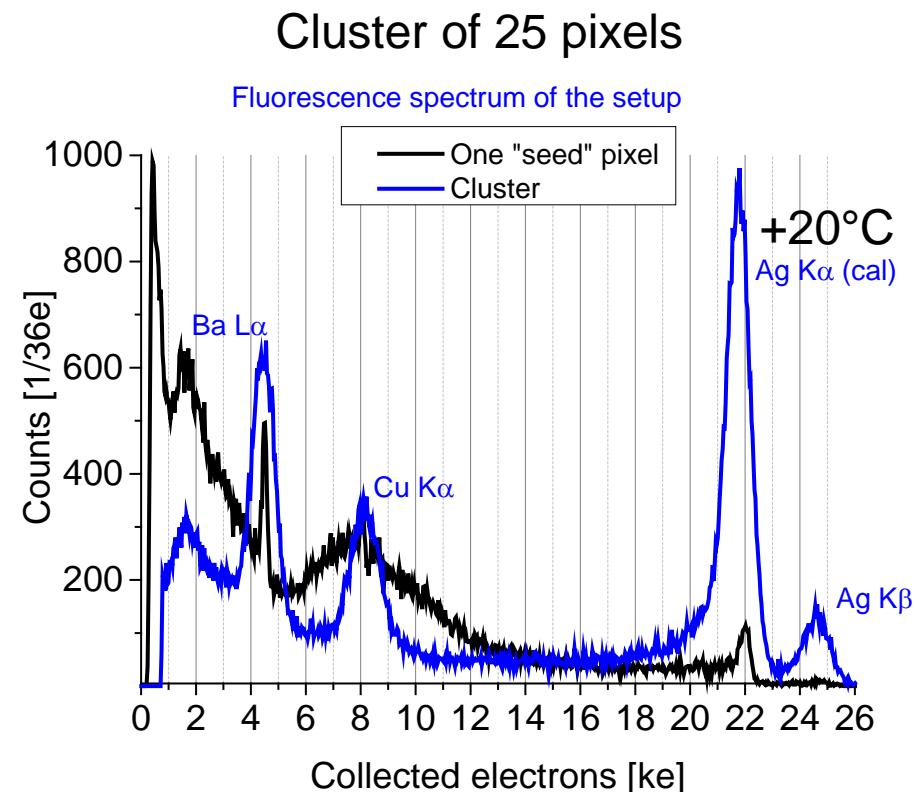
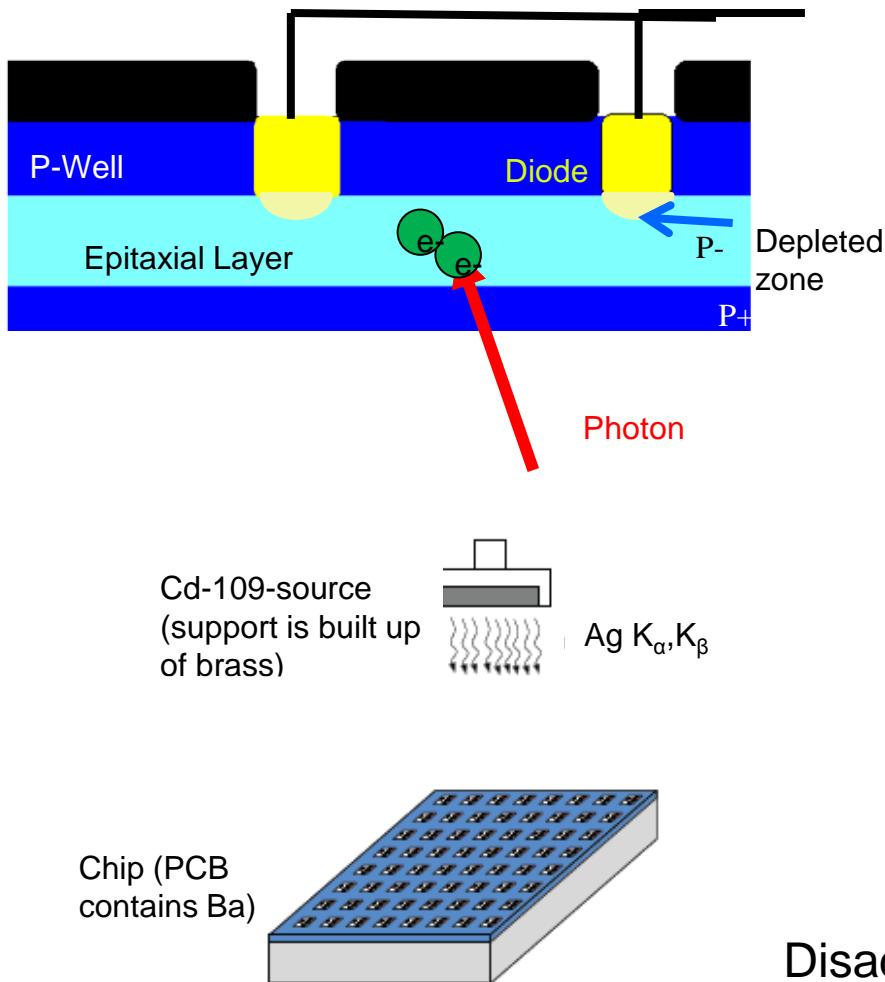


Charge smearing between pixels



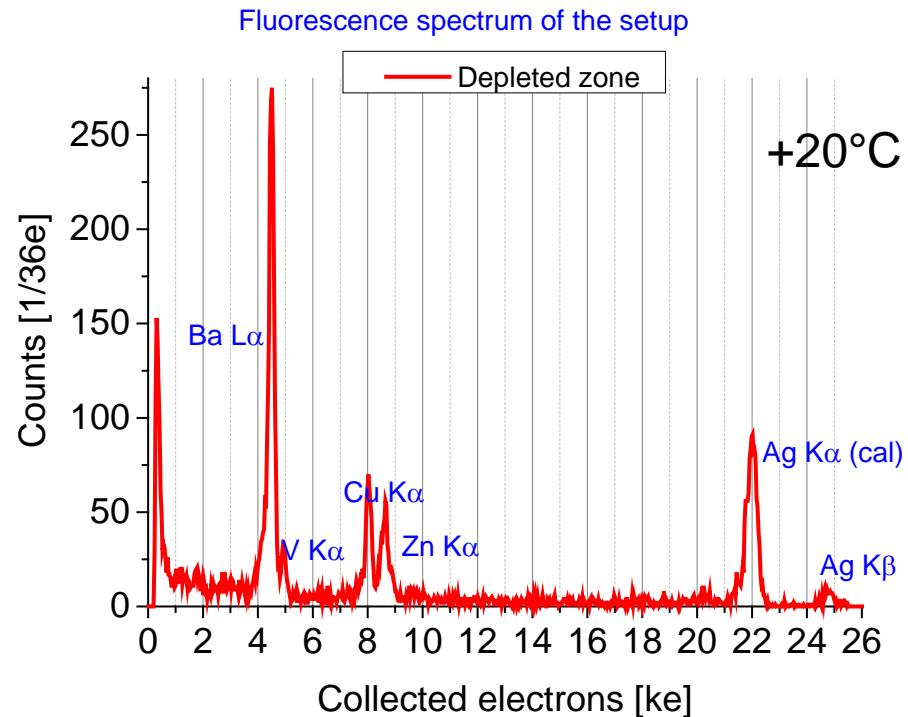
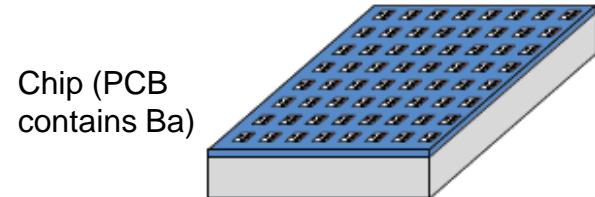
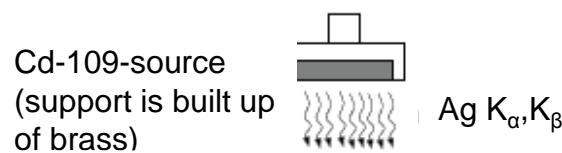
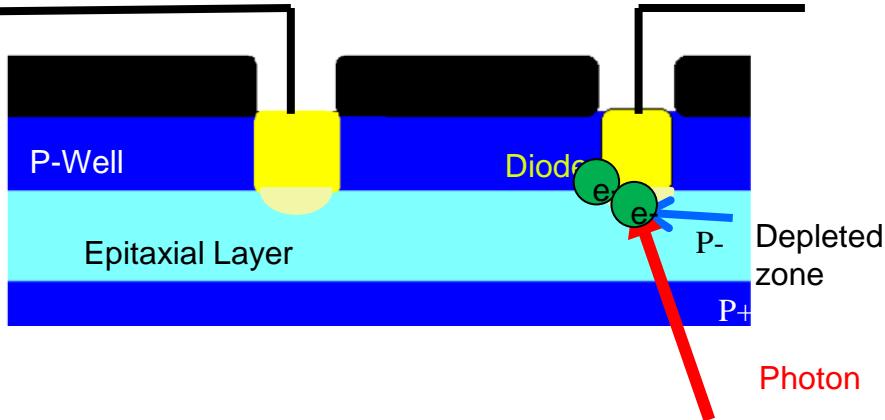
Drawback: Charge smearing

Cluster of 25 pixels



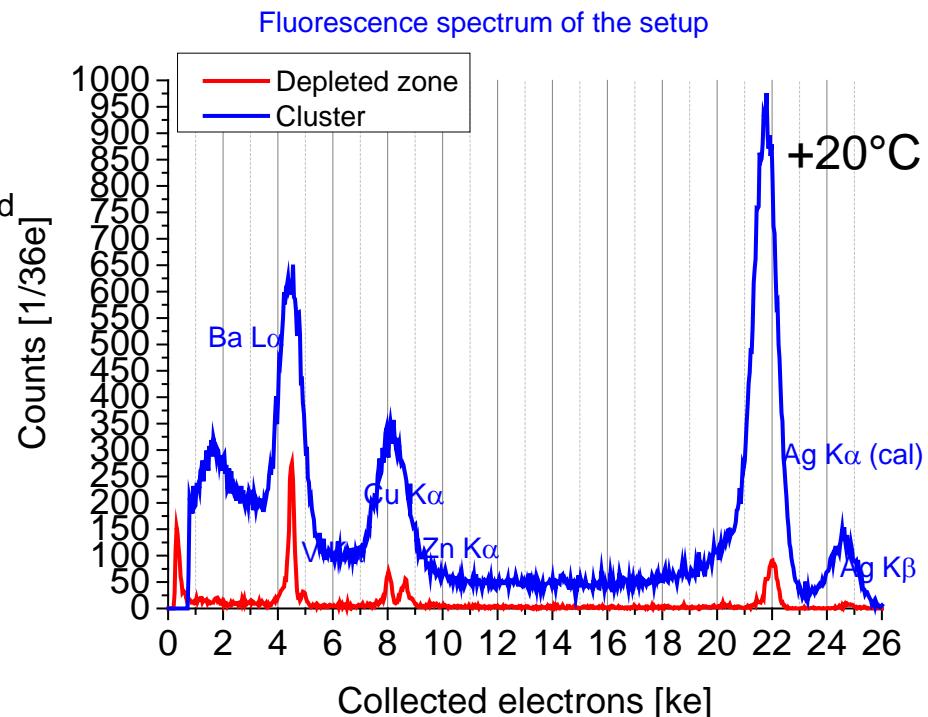
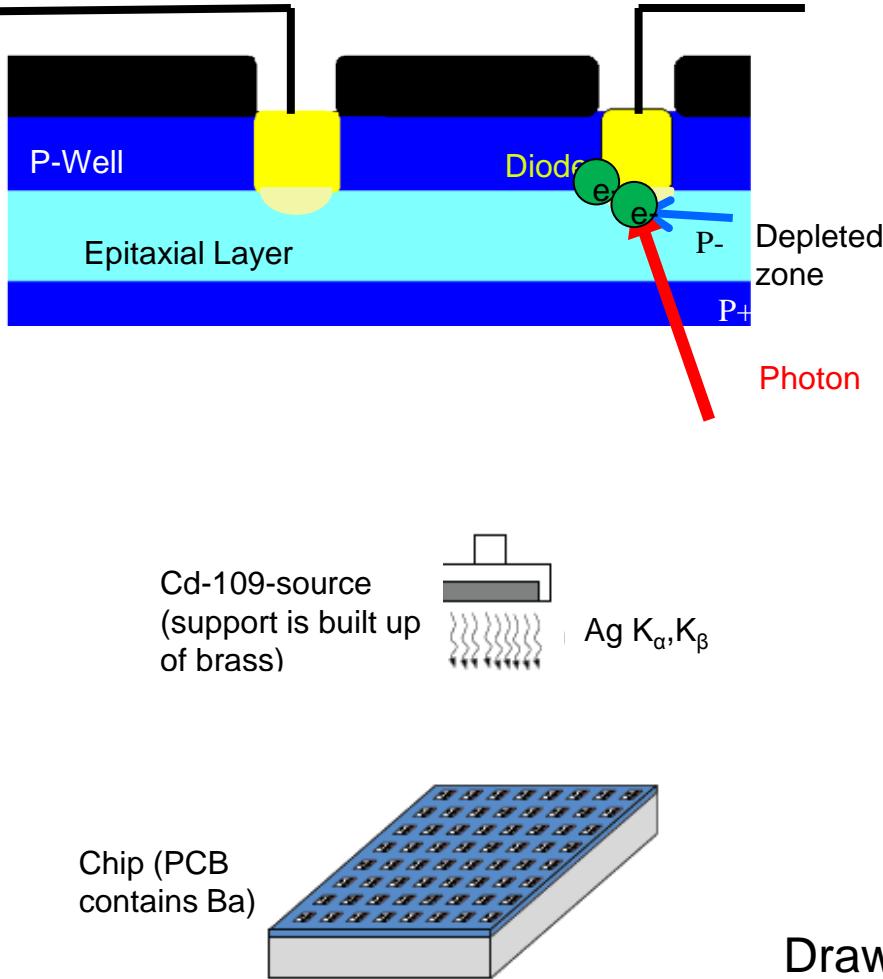
Disadvantage: Noise contribution of 25 pixels

Trigger on conversions in the depleted zone



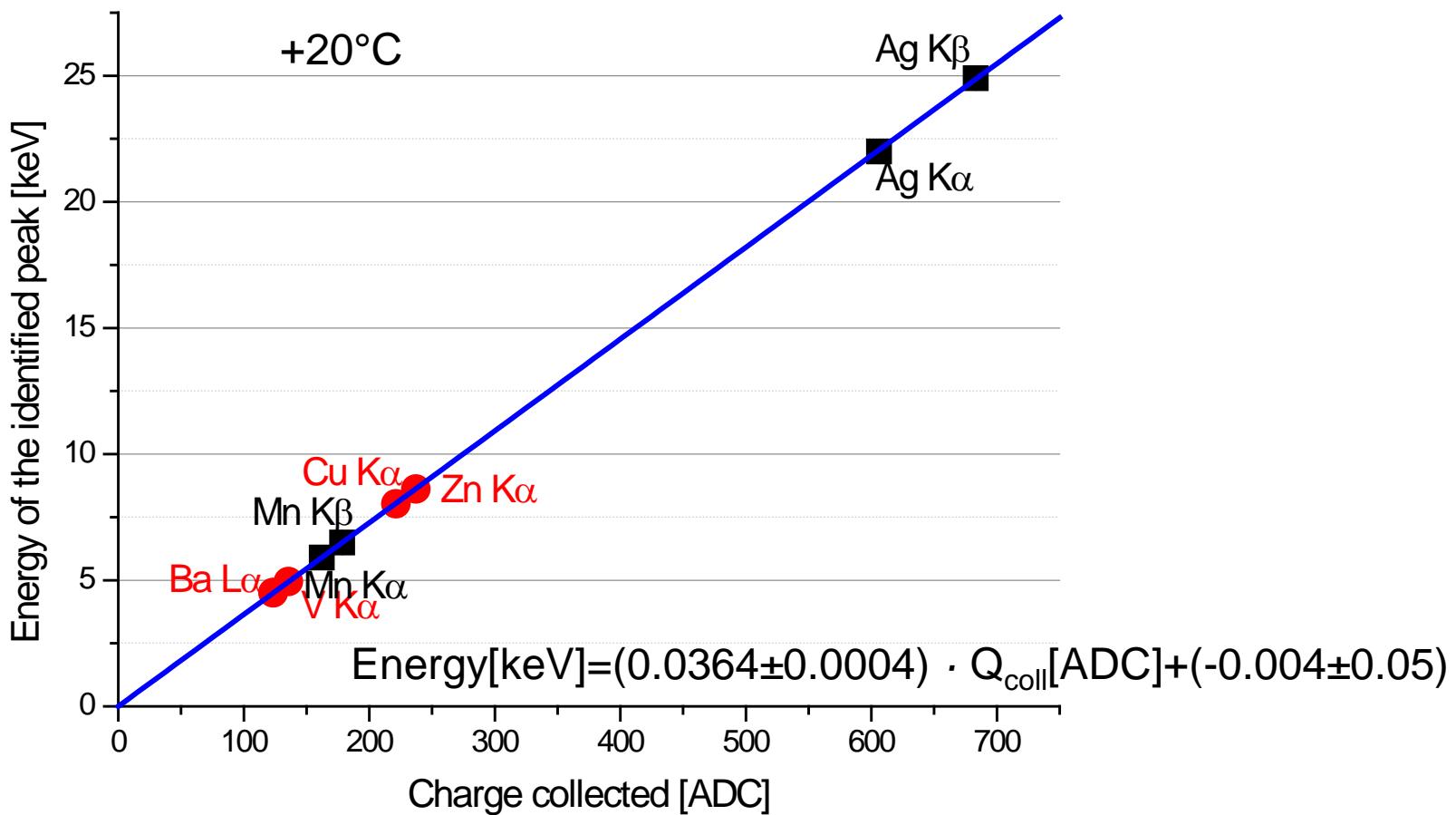
Triggercondition: Neighboring pixel carry no charge

Trigger on conversions in the depleted zone



Drawback: Reduced quantum efficiency

Linearity of amplification chain



Linear energy scale at least between a few keV up to 25keV

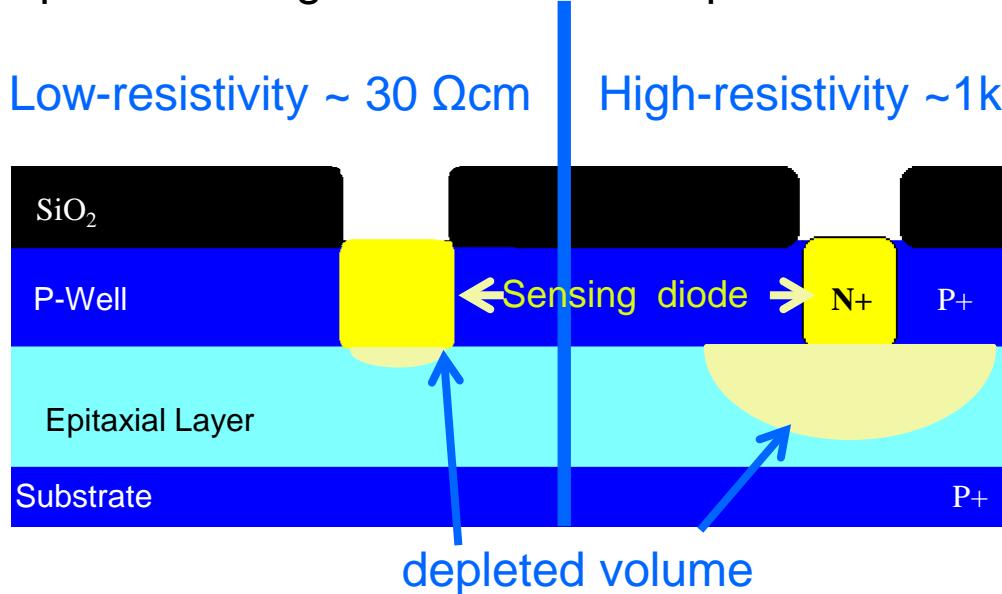
Strategies to increase the quantum efficiency

High-resistivity: Decrease of doping concentration in epitaxial layer.

Depletion voltage: Increase the depleted volume

Low-resistivity $\sim 30 \Omega\text{cm}$

High-resistivity $\sim 1k \Omega\text{cm}$



Larger depleted volumes:

- ⇒ Accelerated charge collection, less diffusion
- ⇒ Less charge smearing between pixels

Aim: Full depletion of the epitaxial layer

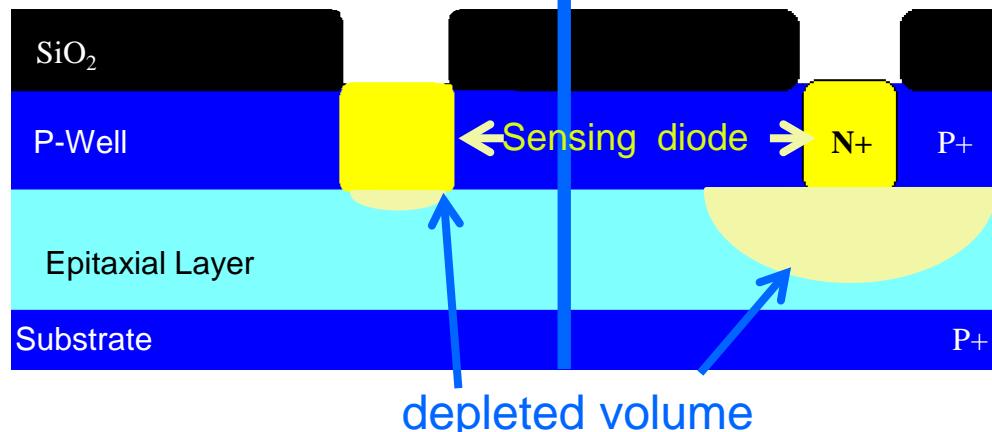
TOWER-Jazz-Process

High-resistivity: Decrease of doping concentration in epitaxial layer.

Depletion voltage: Increase the depleted volume

Low-resistivity $\sim 30 \Omega\text{cm}$

High-resistivity $\sim 1\text{k }\Omega\text{cm}$



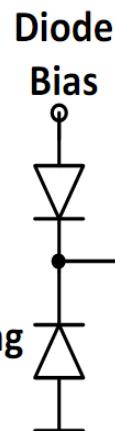
TOWER-Jazz-0.18μm process

- High-Resistivity 1-8kΩcm
- Depletion voltage up to 20V

Larger depleted volumes:

- ⇒ Accelerated charge collection, less diffusion
- ⇒ Less charge smearing between pixels

Aim: Full depletion of the epitaxial layer



Modified preamplifier

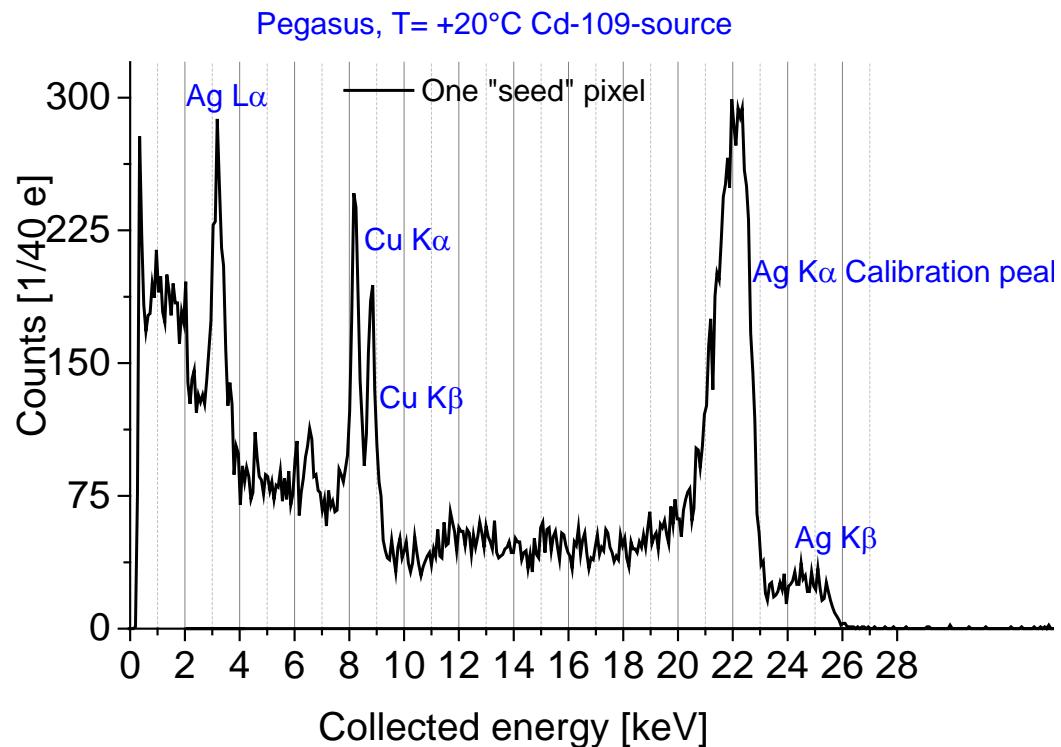
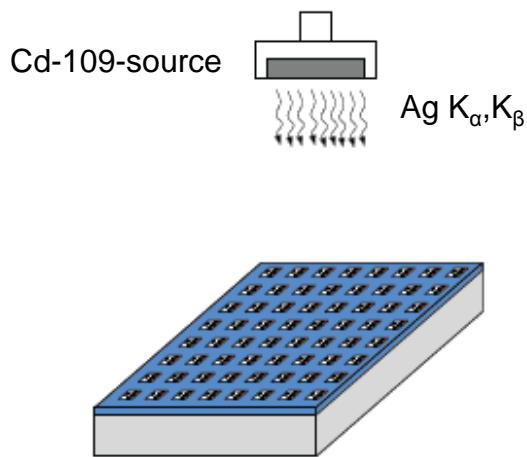
- Recharge diode
- AC-coupled

Collecting diode

TOWER-Jazz 0.18 μ m CMOS process for imager

The Sensor: PEGASUS (2015)

18 μ m thick, 25 μ m pixel pitch, >1k Ω cm epitaxial layer, 12 V bias voltage

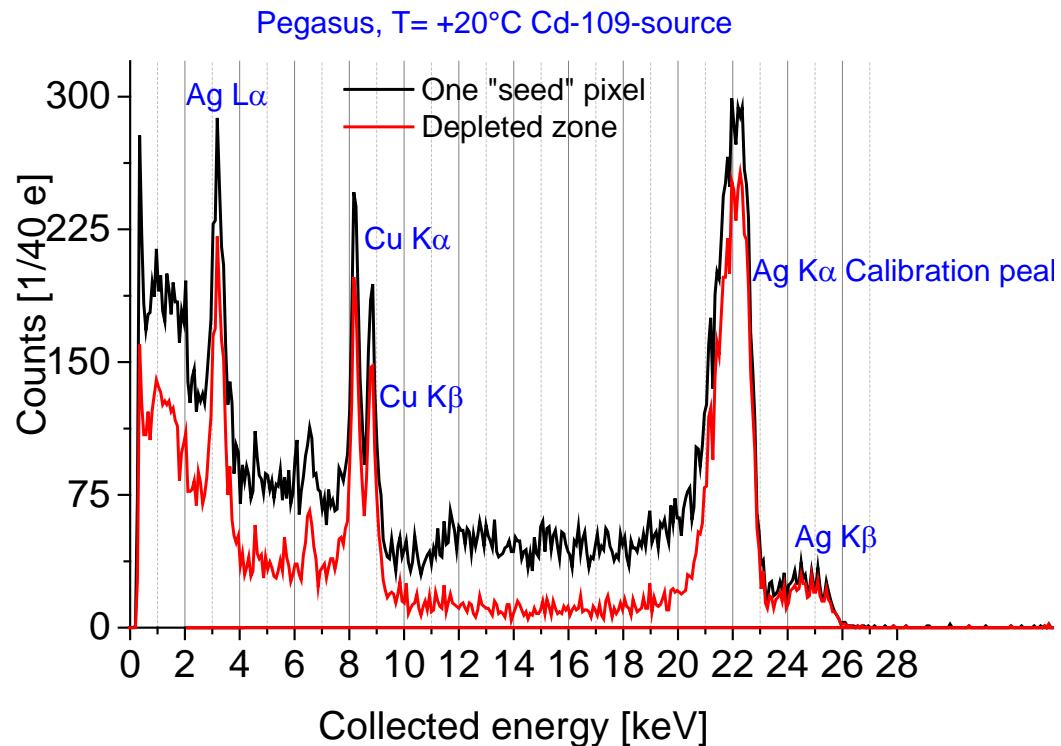
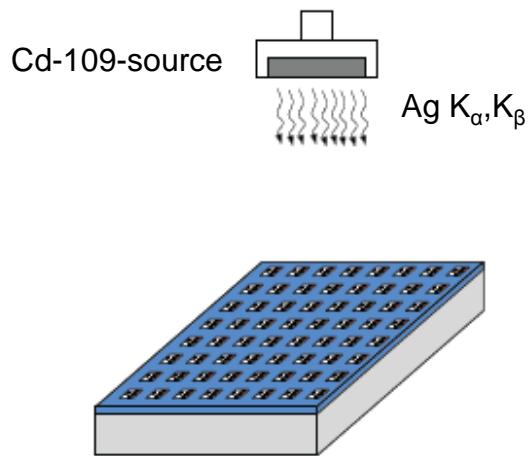


Less charge smearing
 ⇒ Larger depletion zone

TOWER-Jazz 0.18 μ m CMOS process for imager

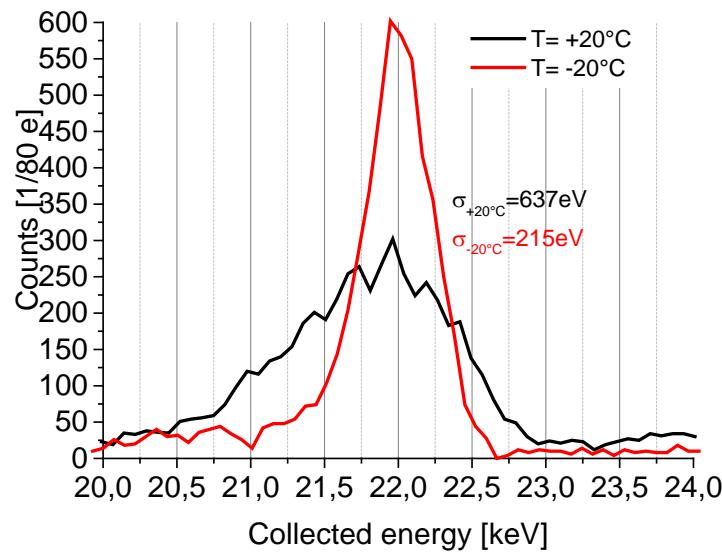
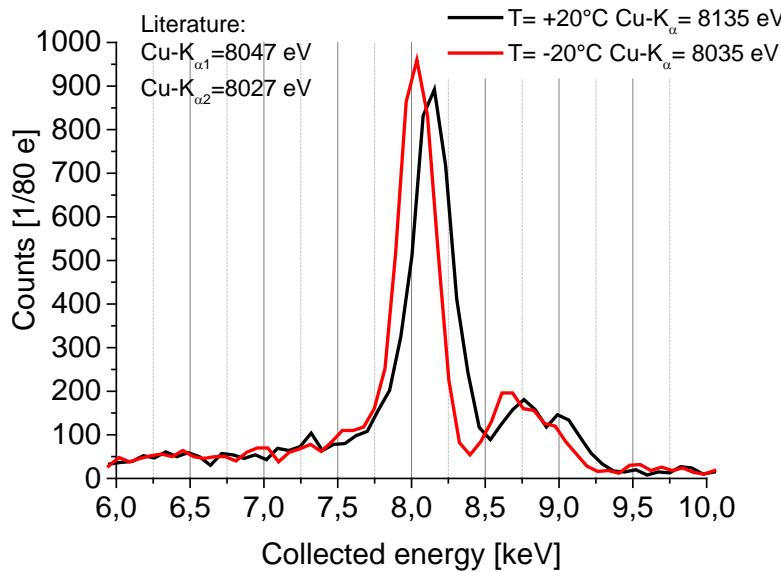
The Sensor: PEGASUS (2015)

18 μ m thick, 25 μ m pixel pitch, >1k Ω cm epitaxial
ayer, 12 V bias voltage



Less charge smearing
 ⇒ Larger depletion zone
 Trigger on neighboring pixels still helps

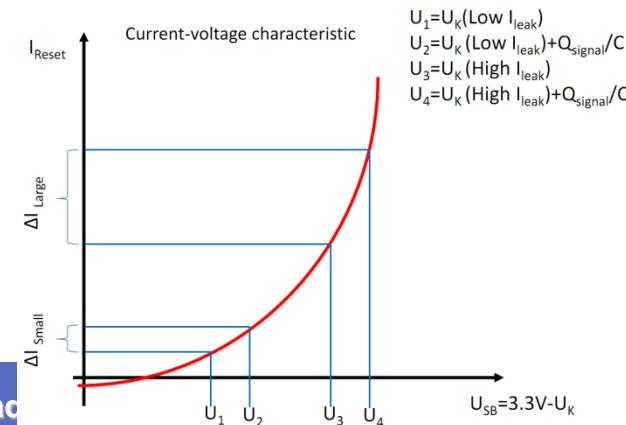
Influence of the leakage current



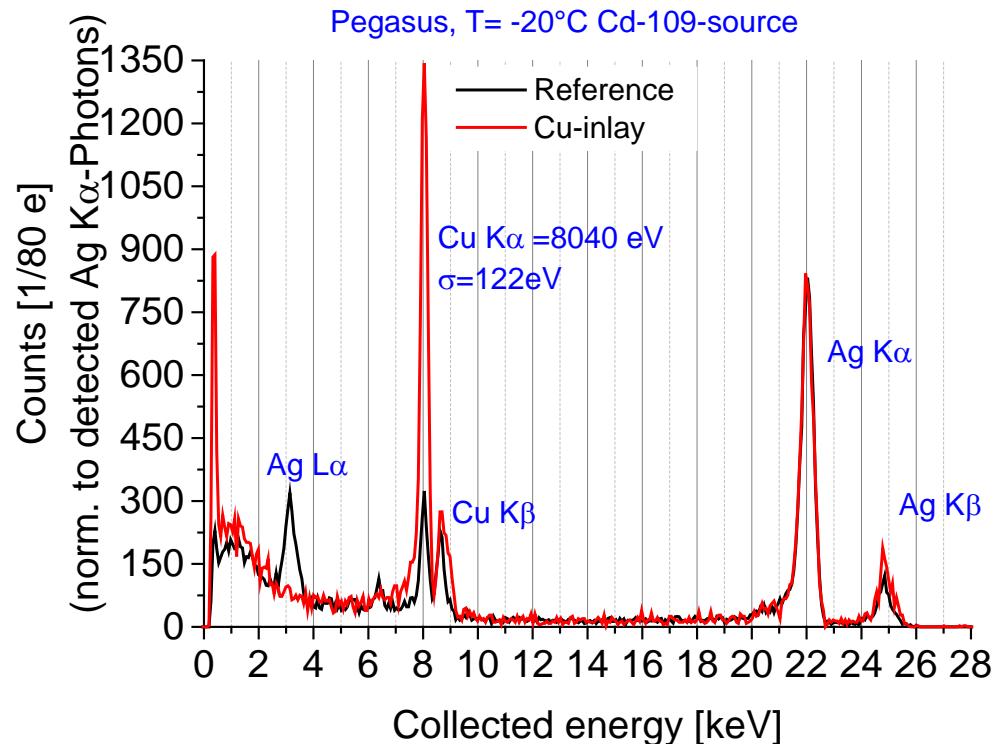
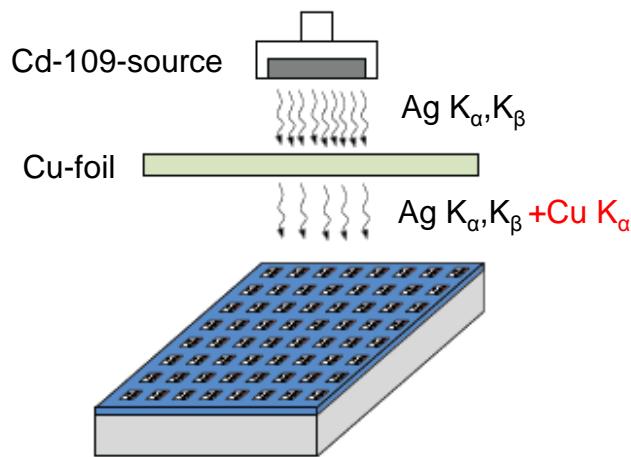
Due to the non-linear response of the recharge diode at $+20^\circ\text{C}$:

- Limited energy resolution
- Non-linear amplification

- ⇒ Optimizing of the pixel layout required (Pegasus-3)
- ⇒ Cooling to -20°C so far helps



Cu-inlay



Expected excess in Cu-K α -line observed
 Energy resolution is $\sigma=122\text{eV}$

Conclusion

Application: Real-time water analysis via X-ray fluorescence analysis

⇒ CMOS-Sensors proposed

Studied two CMOS-sensors: MIMOSA-19 and Pegasus

Possible above 2 keV with an energy resolution of 120...190eV
At room temperature or slightly cooled conditions

⇒ Sensors seem suited for the task

Outlook:

Obtain higher quantum efficiency due to full depleted epitaxial layer
Detailed study of high-voltage CMOS-sensors required

DFG proposal submitted